

*FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		ATTY DOCKET NO. 35.C12395 CIP APPLICANT : YOSHIIHIKO FUKUMOTO FILING DATE : Herewith		APPLICATION NO. : CIP of 08/979,957 and 08/714,437 GROUP: Unassigned	
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584 U.S. P.10
 09/429530
 10/28/99

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<i>de</i>	5665496	9/97	Omika et al.	430	7		
<i>br</i>	5711646	1/98	Ueda et al.	414	225		
<i>br</i>	5853522	12/98	Krusell et al.	156	345		
<i>br</i>	5933204	8/3/99	Fukumoto	349	43	1/96	
<i>de</i>	5767827	6/98	Kobayashi et al.	345	87	12/95	
<i>br</i>	5602423	2/97	Jain	257	752		
<i>br</i>	5426523	6/95	Shimada	359	54		
<i>br</i>	5691794	11/97	Hoshi et al.	349	158		
<i>br</i>	5596230	1/97	Hong	257	755		

FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		
196 25 521	3/21/98	Germany			Abstract		
0 768 710	4/16/97	Europe					
0 692 318	1/17/96	Europe					
0 390 134	10/3/90	Europe					
5-251412	9/93	Japan			Abstract		
5-289925	1/90	Japan			Abstract		

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
<i>de</i>	H. Aoki et al., "Novel Electrolysis Processes", 1994 Symposium on VLSI Tech. Dig. Tech. Papers, June 7-9, 1994, pp. 79-80.

EXAMINER <i>Shawn Lee-Lann</i>	DATE CONSIDERED <i>11/27/00</i>
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1

APPLICATION NO.
09/429.530

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

APPLICANT
YOSHIHIKO FUKUMOTO

FILING DATE **October 28, 1999**

GROUP 1765

U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

[illegible]

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	Shessa Dee Rann	DATE CONSIDERED 11/27/00

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